

<b>Notice of References Cited</b>	Application/Control No. 10/698,472	Applicant(s)/Patent Under Reexamination OGIWARA ET AL.	
	Examiner Ari M. Diacou	Art Unit 3663	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,310,716 B1	10-2001	Evans et al.	359/334
	B	US-6,388,801 B1	05-2002	Sugaya et al.	359/334
	C	US-2002/0060839 A1	05-2002	Oh et al.	359/337.5
	D	US-6,429,966 B1	08-2002	Hazell et al.	359/341.41
	E	US-6,466,362 B1	10-2002	Friedrich, Lars	359/334
	F	US-6,510,000 B1	01-2003	Onaka et al.	359/334
	G	US-2003/0076578 A1	04-2003	Goto et al.	359/337.4
	H	US-2003/0161031 A1	08-2003	Benjamin et al.	359/337.4
	I	US-6,867,905	03-2005	Griseri et al.	359/334
	J	US-6,891,659	05-2005	Kikuchi, Nobuhiko	359/334
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Hecht, Jeff. Understandign fiebr optics 2nd ed. Sams Publishing. 1993 Indianapolis, IN. Pages 209-228.
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.